

**Search Notes**

Application/Control No.

10/524,587

Examiner

Pablo N. Tran

Applicant(s)/Patent under  
Reexamination

SERNA ET AL

Art Unit

2618

**SEARCHED**

Class	Subclass	Date	Examiner
370	320		
	428		
	312		
	329		
	3A1		
	349		
	310		
	347		
	348		
	382		
	427		
	395.82		
	392		
	331		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

**Search Notes (continued)**

Application/Control No.

10/524,587

Examiner

Pablo N. Tran

Applicant(s)/Patent under  
Reexamination

SERNA ET AL

Art Unit

2618

**SEARCHED**

Class	Subclass	Date	Examiner
370	432		
	400		
	252		
	256		
489	802-803		
	486.1		
	486.3		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR